D-408. Exam Schedule

Mon, 25 Dec	09:00 — 12:00	TEST Design of Integrated Circuits and Systems-on-Chip (SOC) M16-406, M17-403 Bakerenkov A.S.
Mon, 25 Dec	12:45 — 14:20	ATT Reliability and Radiation Resistance of Microelectronic Devices and Systems M16-406, M17-403 Zebrev G.I.
Tue, 09 Jan	09:00 — 13:00	EXAM Reliability and Radiation Resistance of Microelectronic Devices and Systems M16-406, M17-403 Zebrev G.I.
Mon, 22 Jan	09:00 — 13:00	EXAM Design of Integrated Circuits and Systems-on-Chip (SOC) M16-406 Bakerenkov A.S.